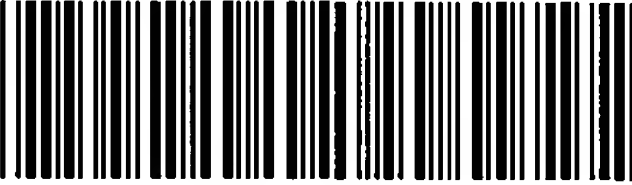


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/663,547	YEN, CHIH-CHEN	
	Examiner	Art Unit	
	KEVIN L. LEE	3753	

SEARCHED			
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137	544-550	6/21/2005	KL
251	40 120		
138	44, 45		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST search	6/21/2005	KL